

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	177	tube with recognition with pattern	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:25
L2	181	tube with recognition with (pattern or waveform)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:27
L3	29	tube near4 recognition with (pattern or waveform)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:30
L4	322	tube near4 recognition	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:33
L5	6	("3202761").URPN.	USPAT	OR	OFF	2007/07/23 12:32
L6	47	tube near4 recognition and camera	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:34
L7	15	tube near4 recognition and camera and inspect\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:40

## EAST Search History

L8	868	tube near4 inspect\$4 and camera	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:41
L9	188	tube near4 inspect\$4 and camera and (opening with tube )	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 12:42
L10	30	tube near4 inspect\$4 and camera with (opening with tube )	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 13:04
L11	68	tube near4 inspect\$4 and cameras with tube	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/23 13:52
L12	87	382/142.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/23 13:59



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Results for "((((tube &lt;near&gt; inspect\*)&lt;in&gt;metadata))&lt;and&gt;('cameras'&lt;in&gt;metadata))"

☐ e-mail

Your search matched 2 of 111 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

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## » Key

IEEE JNL IEEE Journal or Magazine

IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IET CNF IET Conference Proceeding

IEEE STD IEEE Standard

[Select All](#) [Deselect All](#)

- ☐ 1. Inspection of continuously moving metallic tubes by artificial vision: moc results  
Truchetet, F.; Jender, H.; Lew-Yan-Voon, L.F.C.;  
[Industrial Electronics, Control and Instrumentation, 1994. IECON '94., 20th Int Conference on](#)  
Volume 2, 5-9 Sept. 1994 Page(s):749 - 754 vol.2  
Digital Object Identifier 10.1109/IECON.1994.397879  
[AbstractPlus](#) | Full Text: [PDF\(356 KB\)](#) IEEE CNF  
[Rights and Permissions](#)
- ☐ 2. Using computer vision for the automatic inspection and alignment of tele  
Yerem, G.C.; Koch, D.B.;  
[SoutheastCon, 2002. Proceedings IEEE](#)  
5-7 April 2002 Page(s):67 - 72  
Digital Object Identifier 10.1109/2002.995560  
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